	Search Notes		
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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/717,895	MATSUO ET AL.	
Examiner	Art Unit	
David Mis	2817	

	SEAD	CHED	
	JEAR	CHED	
Class	Subclass	Date	Examiner
331	36C,	5/17/2005	DM
	74-77,		
	96,		
	117R,		
	117FE,		
	117D,		
	171,		
_	177V		
UPOA	TED	1/18/6	~~

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
USPGPUB	(see history)	11811	\$v-

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